



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

SP Metrology System (Thailand) Co., Ltd.
69/29 Moo. 1 T. Klongsi A.Klongluang
Pathumthani, Thailand 12120

Fulfills the requirements of

ISO/IEC 17025:2017

In the fields of

CALIBRATION and DIMENSIONAL MEASUREMENT

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 16 May 2022

Certificate Number: ACT-2050



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

SP Metrology System (Thailand) Co., Ltd.

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CALIBRATION AND DIMENSIONAL MEASUREMENT

Valid to: **May 16, 2022**

Certificate Number: **ACT-2050**

CALIBRATION

Acoustics and Vibration

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Sound Level Meter	94 dB 114 dB	0.15 dB 0.15 dB	Sound Level Calibrator
¹ Vibration Meter w/Sensor Acceleration	40 Hz (0 to 50) m/s ² (RMS) 160 Hz (0 to 50) m/s ² (RMS) 1 kHz (0 to 20) m/s ² (RMS) 5 kHz (0 to 20) m/s ² (RMS)	1.6 % of reading 1.5 % of reading 1.5 % of reading 2.4 % of reading	Vibration Calibrator
Velocity	40 Hz (0 to 50) mm/s (RMS) 160 Hz (0 to 50) mm/s (RMS)	1.5 % of reading 2.7 % of reading	
Displacement	40 Hz (0 to 50) μm (RMS) 160 Hz (0 to 50) μm (RMS)	3.2 % of reading 3.2 % of reading	

Chemical Quantities

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
^{1,2} pH Meter	4.01 pH 7.01 pH 10.01 pH	0.012 pH 0.012 pH 0.012 pH	pH Solution Buffer
^{1,2} Conductivity Meter	84 µS/cm 1 413 µS/cm 12 880 µS/cm	0.6 µS/cm 8.2 µS/cm 75 µS/cm	STD Conductivity Solution
¹ Refractometer	5 %Brix 10 %Brix 20 %Brix 30 %Brix 60 %Brix	0.075 %Brix 0.074 %Brix 0.074 %Brix 0.073 %Brix 0.072 %Brix	Sucrose Standard Solution
¹ Refractometer Refractive Index	1.340 27 nD 1.347 84 nD 1.363 85 nD 1.381 14 nD 1.441 89 nD	0.000 11 nD 0.000 11 nD 0.000 11 nD 0.000 11 nD 0.000 11 nD	Sucrose Standard Solution
¹ Turbidity meter	20 NTU 200 NTU 750 NTU	0.12 NTU 1.2 NTU 5.8 NTU	Turbidity Standard Solution
¹ Viscometer Rotational @25°C	101.1 cP 6 618 cP 15 608 cP	0.16 cP 15 cP 36 cP	STD Viscosity Solution
¹ Total Dissolved Solids (TDS) Meter	1 000 mg/l	32 mg/l	TDS Solution

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ RTD Temperature Indicator (Simulator) Temperature Indicator	RTD (Pt100) (-200 to 800) °C 10 Ω, Cu 427 (-100 to 260) °C	0.25 °C 0.42 °C	Fluke 744 Process Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment	
¹ Thermocouple Temperature Indicator (Simulator) Temperature Indicator	Type E (-250 to 1 000) °C	0.42 °C	Fluke 744 Process Calibrator	
	Type J (-210 to 1 200) °C	0.45 °C		
	Type K (-200 to 1 372) °C	0.38 °C		
	Type R and S (0 to 1 768) °C	0.96 °C		
	Type T (-250 to 400) °C	0.64 °C		
¹ DC Voltage Source	Up to < 330 mV	48 μV/V + 9 μV	Fluke 5502A Multiproduct Calibrator	
	330 mV to < 3.3 V	40 μV/V + 60 μV		
	(3.3 to < 33) V	40 μV/V + 0.6 mV		
	(33 to < 330) V	45 μV/V + 6 mV		
	(330 to 1 000) V	45 μV/V + 60 mV		
¹ DC Current Source	Up to < 3.3 mA	0.08 mA/A + 85 nA	Fluke 5502A Multiproduct Calibrator	
	(3.3 to < 33) mA	0.08 mA/A + 0.65 μA		
	(33 to < 330) mA	0.08 mA/A + 7.8 μA		
	(0.33 to < 1.1) A	0.3 mA/A + 80 μA		
	(1.1 to < 3) A	0.3 mA/A + 85 μA		
	(3.0 to < 11) A (11 to 20) A	0.47 mA/A + 0.8 mA 0.78 mA/A + 5.8 mA		
¹ AC Voltage Source	(1 to < 33) mV	Fluke 5502A Multiproduct Calibrator		
	(10 to 45) Hz		1.5 mV/V + 20 μV	
	> 45 Hz to 10 kHz		0.8 mV/V + 20 μV	
	(> 10 to 20) kHz		1.5 mV/V + 20 μV	
	(> 20 to 50) kHz		1.6 mV/V + 20 μV	
	(> 50 to 100) kHz		3 mV/V + 30 μV	
	(> 100 to 450) kHz		8 mV/V + 50 μV	
	(33 to < 330) mV		Fluke 5502A Multiproduct Calibrator	
	(10 to 45) Hz			0.5 mV/V + 20 μV
	> 45 Hz to 10 kHz			0.25 mV/V + 20 μV
	(> 10 to 20) kHz			0.6 mV/V + 20 μV
	(> 20 to 50) kHz			0.8 mV/V + 35 μV
(> 50 to 100) kHz (> 100 to 450) kHz	1.9 mV/V + 0.15 mV 4 mV/V + 0.3 mV			

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment		
¹ AC Voltage Source	(0.33 to < 3.3) V (10 to 45) Hz > 45 Hz to 10 kHz (> 10 to 20) kHz (> 20 kHz to 50) kHz (> 50 kHz to 100) kHz (> 100 kHz to 450) kHz	0.4 mV/V + 80 μV 0.25 mV/V + 0.1 mV 0.6 mV/V + 0.1 mV 0.8 mV/V + 0.1 mV 1.9 mV/V + 0.2 mV 4 mV/V + 0.8 mV	Fluke 5502A Multiproduct Calibrator		
	(3.3 to < 33) V (10 Hz to 45) Hz > 45 Hz to 10 kHz (> 10 kHz to 20) kHz (> 20 kHz to 50) kHz (> 50 kHz to 90) kHz	0.4 mV/V + 0.9 mV 0.25 mV/V + 0.8 mV 0.6 mV/V + 0.9 mV 0.8 mV/V + 0.9 mV 1.9 mV/V + 2 mV			
	(33 to < 330) V 45 Hz to 1 kHz (> 1 to 10) kHz (> 10 kHz to 18) kHz	0.4 mV/V + 7 mV 0.65 mV/V + 10 mV 0.7 mV/V + 15 mV			
	(330 to 1 000) V 45 Hz to 1 kHz (> 1 kHz to 5) kHz (> 5 kHz to 10) kHz	0.4 mV/V + 60 mV 0.65 mV/V + 78 mV 0.7 mV/V + 78 mV			
	¹ AC Current Source	(0.029 to < 0.33) mA (20 Hz to 45) Hz > 45 Hz to 1 kHz (> 1 to 5) kHz (> 5 to 10) kHz		1.6 mA/A + 80 nA 1 mA/A + 80 nA 2.4 mA/A + 0.12 μA 6.3 mA/A + 0.16 μA	Fluke 5502A Multiproduct Calibrator
		(0.33 to < 3.3) mA (20 Hz to 45) Hz > 45 Hz to 1 kHz (> 1 to 5) kHz (> 5 to 10) kHz		1.6 mA/A + 0.15 μA 0.8 mA/A + 0.15 μA 1.6 mA/A + 0.2 μA 4 mA/A + 0.25 μA	
		(3.3 to < 33) mA (20 Hz to 45 Hz > 45 Hz to 1) kHz (> 1 to 5) kHz (> 5 to 10) kHz		1.4 mA/A + 2 μA 0.32 mA/A + 1.8 μA 0.65 mA/A + 1.8 μA 1.6 mA/A + 2.5 μA	



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ AC Current Source	(33 to < 330) mA		Fluke 5502A Multiproduct Calibrator
	(20 Hz to 45) Hz	1.5 mA/A + 18 μ A	
	> 45 Hz to 1 kHz	0.32 mA/A + 18 μ A	
	(> 1 to 5) kHz	0.8 mA/A + 40 μ A	
	(> 5 to 10) kHz	1.6 mA/A + 80 μ A	
	(0.33 to < 1.1) A		
	(20 to 45) Hz	1.4 mA/A + 0.15 mA	
	> 45 Hz to 1 kHz	0.4 mA/A + 0.15 mA	
	(> 1 to 5) kHz	5 mA/A + 0.8 mA	
	(1.1 to < 3) A		
	(45 to 65) Hz	1.5 mA/A + 0.15 mA	
	(> 65 to 500) Hz	0.5 mA/A + 0.15 mA	
> 500 Hz to 1 kHz	0.5 mA/A + 0.15 mA		
(> 1 to 5) kHz	4.8 mA/A + 6 mA		
(3.0 to < 11) A			
(45 to 65) Hz	0.5 mA/A + 1.8 mA		
> 65 Hz to 1 kHz	0.8 mA/A + 2 mA		
(11 to 20) A			
(45 to 65) Hz	0.95 mA/A + 7 mA		
> 65 Hz to 1 kHz	1.2 mA/A + 8.2 mA		
¹ Resistance Source	(0 to 11) Ω	0.1 m Ω / Ω + 10 m Ω	Fluke 5502A Multiproduct Calibrator
	(11 to 33) Ω	0.1 m Ω / Ω + 15 m Ω	
	(33 to 110) Ω	80 $\mu\Omega$ / Ω + 15 m Ω	
	(110 to 330) Ω	80 $\mu\Omega$ / Ω + 20 m Ω	
	330 Ω to 1.1 k Ω	80 $\mu\Omega$ / Ω + 0.1 Ω	
	(1.1 to 3.3) k Ω	80 $\mu\Omega$ / Ω + 0.2 Ω	
	(3.3 to 11) k Ω	80 $\mu\Omega$ / Ω + 0.8 Ω	
	(11 to 33) k Ω	80 $\mu\Omega$ / Ω + 1.2 Ω	
	(33 to 110) k Ω	0.1 m Ω / Ω + 6 Ω	
	(110 to 330) k Ω	0.11 m Ω / Ω + 12 Ω	
	330 k Ω to 1.1 M Ω	0.13 m Ω / Ω + 70 Ω	
	(1.1 to 3.3) M Ω	0.13 m Ω / Ω + 0.15 k Ω	
	(3.3 to 11) M Ω	0.48 m Ω / Ω + 1 k Ω	
(11 to 33) M Ω	0.8 m Ω / Ω + 3 k Ω		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Capacitance Source 10 Hz to 10 kHz 10 Hz to 10 kHz 10 Hz to 3 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 600 Hz 10 Hz to 300 Hz 10 Hz to 150 Hz 10 Hz to 120 Hz 10 Hz to 80 Hz 50 Hz 20 Hz 6 Hz 2 Hz 0.6 Hz 0.2 Hz	(0.1 to 0.5) nF (0.5 to 1.09) nF (1.1 to 3.29) nF (3.3 to 10.9) nF (11 to 32.9) nF (33 to 109.9) nF (110 to 329.9) nF (0.33 to 1.09) μF (1.1 to 3.29) μF (3.3 to 10.9) μF (11 to 32.9) μF (33 to 109.9) μF (110 to 329.9) μF (0.33 to 1.09) mF (1.1 to 3.29) mF (3.3 to 10.9) mF (11 to 32.9) mF (33 to 50) mF	0.4 % of reading + 8pF 0.4 % of reading + 10 pF 0.4 % of reading + 10 pF 0.2 % of reading + 12 pF 0.2 % of reading + 0.1 nF 0.2 % of reading + 0.1 nF 0.2 % of reading + 0.7 nF 0.2 % of reading + 1.3 nF 0.2 % of reading + 7 nF 0.2 % of reading + 10 nF 0.32 % of reading + 0.08 μF 0.37 % of reading + 0.11 μF 0.37 % of reading + 0.7 μF 0.37 % of reading + 1 μF 0.37 % of reading + 6.5 μF 0.37 % of reading + 10 μF 0.6 % of reading + 63 μF 0.85 % of reading + 98 μF	Fluke 5502A Multiproduct Calibrator
¹ DC Current Clamp Source	Up to 200 A (> 200 to 550) A (> 550 to 1 000) A	3.8 mA/A + 60 mA 3.3 mA/A + 80 mA 3.2 mA/A + 70 mA	Fluke 5502A Multiproduct Calibrator with Current Coil
¹ AC Current Clamp Source	Up to 20 A (45 to 100) Hz (> 100 to 440) Hz (> 20 to 200) A (45 to 65) Hz (> 65 to 100) Hz (> 100 to 440) Hz (> 200 to 550) A (45 to 65) Hz (> 65 to 100) Hz (> 550 to 1 000) A (45 to 65) Hz (> 65 to 100) Hz	5 mA/A + 80 mA 12 mA/A + 80 mA 5 mA/A + 80 mA 9.5 mA/A + 80 mA 14 mA/A + 80 mA 3.7 mA/A + 72 mA 9 mA/A + 60 mA 3.7 mA/A + 80 mA 9.3 mA/A + 80 mA	Fluke 5502A Multiproduct Calibrator with Current Coil

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Insulation Resistance Source Test Voltage @ 50 V, 100 V, 250 V, 500 V, 1 000 V	(0.1 to 10) MΩ	5.8 kΩ	Resistance Decade Box
	(10 to 20) MΩ	32 kΩ	
	(20 to 30) MΩ	69 kΩ	
	(30 to 50) MΩ	75 kΩ	
	(50 to 100) MΩ	94 kΩ	
	(100 to 200) MΩ	2.8 MΩ	
	(200 to 500) MΩ	4.5 MΩ	
¹ Electrical Simulation of Thermocouple Indicating Devices – Source/Measure	Type K		Fluke 5502A Multiproduct Calibrator
	(-200 to -100) °C	0.46 °C	
	(-100 to -25) °C	0.26 °C	
	(-25 to 120) °C	0.23 °C	
	(120 to 1 000) °C	0.37 °C	
	(1 000 to 1 372) °C	0.56 °C	
	Type B		
	(600 to 800) °C	0.61 °C	
	(800 to 1 000) °C	0.48 °C	
	(1 000 to 1 550) °C	0.42 °C	
	(1 550 to 1 820) °C	0.46 °C	
	Type E		
	(-250 to -100) °C	0.7 °C	
	(-100 to -25) °C	0.23 °C	
	(-25 to 350) °C	0.2 °C	
	(350 to 650) °C	0.23 °C	
	(650 to 1 000) °C	0.3 °C	
	Type J		
	(-210 to -100) °C	0.56 °C	
	(-100 to -25) °C	0.32 °C	
	(-25 to 150) °C	0.28 °C	
	(150 to 760) °C	0.24 °C	
	(760 to 1 200) °C	0.33 °C	
Type N			
(-250 to -100) °C	0.56 °C		
(-100 to -25) °C	0.32 °C		
(-25 to 120) °C	0.28 °C		
(120 to 410) °C	0.26 °C		
(410 to 1 300) °C	0.38 °C		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment		
¹ Electrical Simulation of Thermocouple Indicating Devices – Source/Measure	Type R (0 to 250) °C (250 to 400) °C (400 to 1 000) °C (1 000 to 1 767) °C	0.8 °C 0.5 °C 0.47 °C 0.56 °C	Fluke 5502A Multiproduct Calibrator		
	Type S (0 to 250) °C (250 to 400) °C (400 to 1 000) °C (1 000 to 1 767) °C	0.66 °C 0.51 °C 0.52 °C 0.65 °C			
	Type U (-200 to 0) °C (0 to 600) °C	0.79 °C 0.38 °C			
	Type T (-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.88 °C 0.34 °C 0.23 °C 0.21 °C			
	¹ Electrical Simulation of RTD Indicating Devices – Source	100 Ω, Pt385 (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C		0.09 °C 0.09 °C 0.14 °C 0.14 °C 0.15 °C 0.18 °C 0.33 °C	Fluke 5502A Multiproduct Calibrator
		200 Ω, Pt385 (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C		0.08 °C 0.08 °C 0.08 °C 0.09 °C 0.18 °C 0.19 °C 0.2 °C 0.23 °C	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Electrical Simulation of RTD Indicating Devices – Source	500 Ω, Pt385		Fluke 5502A Multiproduct Calibrator
	(-200 to -80) °C	0.08 °C	
	(-80 to 0) °C	0.09 °C	
	(0 to 100) °C	0.09 °C	
	(100 to 260) °C	0.1 °C	
	(260 to 300) °C	0.13 °C	
	(300 to 400) °C	0.13 °C	
	(400 to 600) °C	0.14 °C	
	(600 to 630) °C	0.16 °C	
	1 000 Ω, Pt385		
	(-200 to -80) °C	0.08 °C	
	(-80 to 0) °C	0.09 °C	
	(0 to 100) °C	0.09 °C	
	(100 to 260) °C	0.1 °C	
	(260 to 300) °C	0.13 °C	
	(300 to 400) °C	0.13 °C	
	(400 to 600) °C	0.14 °C	
	(600 to 630) °C	0.16 °C	
	100 Ω, Pt3916		
	(-200 to -190) °C	0.36 °C	
	(-190 to -80) °C	0.08 °C	
	(- 80 to 0) °C	0.09 °C	
	(0 to 100) °C	0.11 °C	
	(100 to 260) °C	0.11 °C	
	(260 to 300) °C	0.13 °C	
	(300 to 400) °C	0.14 °C	
	(400 to 600) °C	0.15 °C	
	(600 to 630) °C	0.33 °C	
100 Ω, Pt3926			
(-200 to - 80) °C	0.08 °C		
(-80 to 0) °C	0.09 °C		
(0 to 100) °C	0.12 °C		
(100 to 300) °C	0.14 °C		
(300 to 400) °C	0.16 °C		
(400 to 630) °C	0.18 °C		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ DC Power Source	(0.33 to 1 000) V, < 0.33 A (0.108 9 to < 330) W	0.10 mW/W + 6 mW	Fluke 5502A Multiproduct Calibrator
	(0.33 to 1 000) V, (0.33 to < 3) A (330 to < 3.0) kW	0.31 mW/W + 60 mW	
	(0.33 to 1 000) V, (3 to < 10.9) A (3.0 to < 10.9) kW	0.5 mW/W + 0.6 W	
	(0.33 to 1 000) V, (10.99 to 20) A (10.9 to 20) kW	0.81 mW/W + 0.6 W	
¹ AC Power Source	(45 to 65) Hz, PF=1 (0.33 to 1 000) V up to 0.329 A (0.109 to < 10.9) W (10.9 to < 330) W	0.55 mW/W + 1.5 mW 0.8 mW/W + 6 mW	Fluke 5502A Multiproduct Calibrator
¹ AC Power Source	(0.33 to 1 000) V, (0.33 to < 3) A 330 W to < 3 kW	1.2 mW/W + 60 mW	Fluke 5502A Multiproduct Calibrator
	(0.33 to 1 000) V, (3 to < 10.9) A (3 to < 3.5) kW (3.5 to < 10.9) kW	1.4 mW/W + 60 mW 1.4 mW/W + 0.6 W	
	(0.33 to 1 000) V, (10.9 to 20) A (10.9 to 20) kW	1.2 mW/W + 0.6 W	
¹ DC Voltage Measure	Up to 100 mV (> 0.1 to 1) V (> 1 to 10) V (> 10 to 100) V (>100 to 1 000) V	14 μV/V + 0.35 μV 4.9 μV/V + 0.35 μV 4.7 μV/V + 0.58 μV 7 μV/V + 35 μV 21 μV/V + 0.12 mV	HP 3458A 8.5 Digit Multimeter
¹ AC Voltage Measure	100 mV to 10 V (10 to 50) Hz > 50 Hz to 1 kHz (> 1 to 20) kHz (> 20 to 50) kHz (> 50 to 100) kHz (> 100 to 300) kHz > 300 kHz to 1 MHz	85 μV/V + 0.46 mV 85 μV/V+0.23 mV 0.16 mV/V+0.23 mV 0.35 mV/V +0.23 mV 0.93 mV/V+0.23 mV 3.5 mV/V+1.2 mV 12 mV/V+1.2 mV	HP 3458A 8.5 Digit Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ AC Voltage Measure	(> 10 to 100) V (10 to 50) Hz > 50 Hz to 1kHz (> 1 to 20) kHz (> 20 to 50) kHz (> 50 to 100) kHz	0.23 mV/V + 4.6 mV 0.23 mV/V + 2.3 mV 0.23 mV/V + 2.3 mV 0.41 mV/V + 2.3 mV 1.4 mV/V + 2.3 mV	HP 3458A 8.5 Digit Multimeter
	(> 100 to 1 000) V (10 to 50) Hz > 50 Hz to 1 kHz (> 1 to 20) kHz (> 20 to 50) kHz (> 50 to 100) kHz	0.46 mV/V + 46 mV 0.46 mV/V + 23 mV 0.69 mV/V + 23 mV 1.4 mV/V + 23 mV 3.5 mV/V + 23 mV	
¹ DC Current Measure	(> 10 to 100) μA	24 μA/A + 0.92 nA	HP 3458A 8.5 Digit Multimeter
	(> 0.1 to 1) mA	24 μA/A + 5.8 nA	
	(> 1.0 to 10) mA	24 μA/A + 58 nA	
	(> 10 to 100) mA	41 μA/A + 0.58 μA	
	(> 0.10 to 1.0) A	0.13 mA/A + 12 μA	
¹ DC Current Measure	(>1 to 3) A	2.4 mA/A + 1.1 mA	Keysight 34460A 6.5 Digit Multimeter
¹ AC Current Measure	(0.1 to 1) mA (10 to 20) Hz (>20 to 45) Hz (>45 to 100) Hz >100 Hz to 1 kHz	4.6 mA/A + 0.35 μA 1.7 mA/A + 0.35 μA 0.7 mA/A + 0.35 μA 0.7 mA/A + 0.35 μA	HP 3458A 8.5 Digit Multimeter
	(1 to 100) mA (10 to 20) Hz (>20 to 45) Hz (>45 to 100) Hz >100 Hz to 1 kHz	4.6 mA/A + 0.23 mA 1.7 mA/A + 23 μA 0.7 mA/A + 23 μA 0.35 mA/A + 23 μA	
	(0.1 to 1) A (10 to 20) Hz (>20 to 45) Hz (>45 to 100) Hz >100 Hz to 1 kHz	4.6 mA/A + 0.23 mA 1.8 mA/A + 0.23 mA 0.93 mA/A + 0.23 mA 1.2 mA/A + 0.23 mA	
	(0.1 to 1) mA	4.6 mA/A + 0.35 μA	
	(1 to 10) mA	4.6 mA/A + 0.23 mA	
	(10 to 100) mA	1.7 mA/A + 0.35 μA	
	(0.1 to 1) A	0.7 mA/A + 0.35 μA	
	(1 to 10) A	0.35 mA/A + 23 μA	
	(10 to 100) A	4.6 mA/A + 0.23 mA	
	(1 to 10) A	1.8 mA/A + 0.23 mA	
	(10 to 100) A	0.93 mA/A + 0.23 mA	
	(1 to 10) A	1.2 mA/A + 0.23 mA	
¹ AC Current Measure	(>1 to 3) A 50 Hz to 5 kHz	2.7 mA/A + 2 mA	Keysight 34460A 6.5 Digit Multimeter



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Resistance Measure	Up to 10 Ω (> 10 to 100) Ω > 100 Ω to 1 kΩ (> 1 to 10) kΩ (> 10 to 100) kΩ (> 0.1 to 1) MΩ (> 1 to 10) MΩ (> 10 to 100) MΩ > 100 MΩ to 1 GΩ	18 μΩ/Ω + 58 μΩ 14 μΩ/Ω + 0.58 mΩ 12 μΩ/Ω + 0.58 mΩ 1 μΩ/Ω + 5.8 mΩ 12 μΩ/Ω + 58 mΩ 19 μΩ/Ω + 2.3 Ω 59 μΩ/Ω + 0.12 kΩ 0.58 mΩ/Ω + 1.2 kΩ 5.8 mΩ/Ω + 12 kΩ	HP 3458A 8.5 Digit Multimeter
¹ DC High Voltage Measure	Up to 1 kV (> 1 to 3) kV (> 3 to 5) kV (> 5 to 10) kV	24 mV/V + 60 μV 24 mV/V + 70 μV 24 mV/V + 90 μV 24 mV/V + 0.18 mV	Keysight 34460A 6.5 Digit Multimeter with Fluke 80K-40 High Voltage Probe
¹ AC High Voltage Measure	(1 to 6) kV (50 to 60) Hz	58 mV/V + 4 mV	Keysight 34460A 6.5 Digit Multimeter with Fluke 80K-40 High Voltage Probe
LCR Meter Inductance (L)	1 μH to 10 H @ 100 mV, 1 V, 1 kHz	1.2 % of reading + 0.9 μH	IET 1492 Decade Inductor
LCR Meter Capacitance (C)	1 pF to 1 μF @ 1 V, 1 kHz	0.06 % of reading + 0.6 pF	General Radio 1413 Precision Decade Capacitor
LCR Meter Resistance (R)	1 Ω to 100 kΩ @ 1 V, 1 kHz	0.2 % of reading + 2.4 mΩ	Decade Resistance Box
Inductance Source	1 μH to 10 H @ 1 V, 1 kHz	0.06 % of reading	Agilent E4980A LCR Meter
Capacitance Source	1pF to 1μF @ 1 V, 0.1 kHz to 1 MHz	0.06 % of reading	Agilent E4980A LCR Meter
¹ Oscilloscope Vertical deflection DC 50 Ω and 1 MΩ	2 mV 5 mV 10 mV 20 mV 50 mV 100 mV 200 mV 500 mV 1 V 2 V 5 V 10 V 20 V	0.84 % of reading 0.49 % of reading 0.34 % of reading 0.26 % of reading 0.29 % of reading 0.23 % of reading 0.21 % of reading 0.28 % of reading 0.27 % of reading 0.22 % of reading 0.28 % of reading 0.2 % of reading 0.2 % of reading	Fluke 5502A Multiproduct Calibrator, Fluke PM6685R Universal Frequency Counter, HP 3458A 8.5 Digit Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Oscilloscope Vertical Bandwidth 3 dB down from reference amplitude	50 kHz to 100 MHz (>100 to 300) MHz	1.4 % of reading 1.8 % of reading	Fluke 5502A Multiproduct Calibrator, Fluke PM6685R Universal Frequency Counter, HP 3458A 8.5 Digit Multimeter
¹ Oscilloscope Horizontal deflection: Time Mark	1 ns 2 ns 5 ns 10 ns 20 ns 50 ns 100 ns 200 ns 500 ns 1 μs 2 μs 5 μs	0.01 % of reading 0.04 % of reading 0.01 % of reading 0.01 % of reading 0.04 % of reading 0.01 % of reading 0.01 % of reading 0.04 % of reading 0.01 % of reading 0.01 % of reading 0.04 % of reading 0.01 % of reading	Fluke 5502A Multiproduct Calibrator
¹ Oscilloscope Horizontal deflection: Time Mark	10 μs 20 μs 50 μs 100 μs 200 μs 500 μs 1 ms 2 ms 5 ms 10 ms 20 ms 50 ms 100 ms 200 ms 500 ms 1 s 2 s 5 s 10 s	0.01 % of reading 0.04 % of reading 0.01 % of reading 0.01 % of reading 0.04 % of reading 0.01 % of reading 0.01 % of reading 0.04 % of reading 0.01 % of reading 0.01 % of reading 0.04 % of reading 0.01 % of reading 0.01 % of reading 0.04 % of reading 0.01 % of reading 0.62 % of reading 1.2 % of reading 3.1 % of reading 6.2 % of reading	Fluke 5502A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Oscilloscope DC accuracy 50 Ω and 1 MΩ (Digital)	2 mV 5 mV 10 mV 20 mV 50 mV 100 mV 200 mV 500 mV 1 V 2 V 5 V 10 V 20 V	0.11 % of reading 0.39 % of reading 0.19 % of reading 0.1 % of reading 0.38 % of reading 0.19 % of reading 0.1 % of reading 0.38 % of reading 0.19 % of reading 0.1 % of reading 0.04 % of reading 0.02 % of reading 0.01 % of reading	Fluke 5502A Multiproduct Calibrator, Fluke PM6685R Universal Frequency Counter, HP 3458A 8.5 Digit Multimeter
^{1,3} Oscilloscope Time base	10 MHz	$2.4 \times 10^{-10} f$	Fluke 5502A Multiproduct Calibrator, Fluke PM6685R Universal Frequency Counter, HP 3458A 8.5 Digit Multimeter
¹ Oscilloscope Calibrator calibration	≤ 10 Vp-p @ ≤ 10 kHz	0.02 % of reading	Fluke 5502A Multiproduct Calibrator, Fluke PM6685R Universal Frequency Counter, HP 3458A 8.5 Digit Multimeter
Rise Time, Fall Time, Phase Source	Rise/Fall Time 10 ns to 10 ms Phase 0 ° to 360 °	2 ns 1.2 °	Fluke PM6685R Universal Frequency Counter, Agilent 53132A Universal Frequency Counter
Single and Three Phase Power Meter	AC Voltage @ 50/60 Hz (0 to 600) V AC Current @ 50/60 Hz (0 to 1 000) A AC Power @ 50/60 Hz (0 to 60) kW Power Factor (0.5 to 1)	0.58 % of reading 1.3 % of reading 1.3 % of reading 1.2 % of reading	Power Meter, Hioki 3197 And Clamp Sensor, Hioki 9669 (Compare with Power Meter Standard)

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
⁴ Tuned RF Level Measure 10 dB/step	(-40 to 0) dB		HP 8902A Measuring Receiver, HP 11722A/11792A Power Sensor
	10 MHz	0.11 dB	
	50 MHz	0.10 dB	
	100 MHz	0.10 dB	
	400 MHz	0.10 dB	
	1 000 MHz	0.10 dB	
	2 000 MHz	0.11 dB	
	3 000 MHz	0.11 dB	
	4 000 MHz	0.13 dB	
	5 000 MHz	0.11 dB	
	6 000 MHz	0.13 dB	
7 000 MHz	0.17 dB		
8 000 MHz	0.15 dB		
9 000 MHz	0.12 dB		
⁴ Tuned RF Level Measure 10 dB/step	(-40 to 0) dB		HP 8902A Measuring Receiver, HP 11722A/11792A Power Sensor
	1 0000 MHz	0.12 dB	
	11 000 MHz	0.11 dB	
	12 000 MHz	0.16 dB	
	13 000 MHz	0.15 dB	
	14 000 MHz	0.14 dB	
	15 000 MHz	0.23 dB	
	16 000 MHz	0.26 dB	
	17 000 MHz	0.17 dB	
18 000 MHz	0.21 dB		
Distortion Source	@ 20 Hz to 20 kHz (-80 to -40) dB	1.2 dB	HP 8903B Audio Analyzer
	@ (>20 to 100) kHz (-80 to -40) dB	2.3 dB	

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ External Micrometer V-Anvil, Screw Thread, Indicating	Up to 100 mm	1.5 µm	Gauge Block Set, Optical Flats
	(100 to 125) mm	1.8 µm	
	(125 to 150) mm	2.1 µm	
	(150 to 175) mm	2.4 µm	
	(175 to 200) mm	2.8 µm	
	(200 to 250) mm	3.4 µm	
	(250 to 300) mm	4.1 µm	
	(300 to 400) mm	5.4 µm	
	(400 to 500) mm	6.8 µm	
	(500 to 600) mm (600 to 1 000) mm	8.1 µm 13.5 µm	
¹ Vernier Caliper Dial and Digital	Up to 200 mm	0.006 mm	Gauge Block Set
	(200 to 300) mm	0.007 mm	
	(300 to 400) mm	0.008 mm	
	(400 to 500) mm	0.009 mm	
	(500 to 600) mm	0.010 mm	
	(600 to 700) mm	0.011 mm	
	(700 to 800) mm	0.012 mm	
	(800 to 900) mm	0.013 mm	
	(900 to 1 000) mm (1 000 to 1 500) mm	0.015 mm 0.021 mm	
	¹ Can Seam Micrometer	Up to 13 mm	
¹ Internal Micrometer All type Snap Micrometer (Up to 100 mm)	Up to 30 mm	0.7 µm	Gauge Block Set
	(30 to 45) mm	0.8 µm	
	(45 to 50) mm	0.9 µm	
	(50 to 60) mm	1 µm	
	(60 to 70) mm	1.1 µm	
	(70 to 80) mm	1.2 µm	
	(80 to 87) mm	1.3 µm	
	(87 to 97) mm	1.4 µm	
	(97 to 100) mm	1.5 µm	
	(100 to 125) mm	1.8 µm	
	(125 to 150) mm	2.1 µm	
	(150 to 175) mm	2.4 µm	
	(175 to 200) mm	2.8 µm	
	(200 to 250) mm	3.4 µm	
	(250 to 300) mm	4.1 µm	
	(300 to 400) mm	5.4 µm	
	(400 to 500) mm (500 to 600) mm	6.8 µm 8.1 µm	

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Caliper Gauge External	Up to 25 mm (25 to 50) mm	1.2 µm 1.3 µm	Gauge Blocks
¹ Caliper Gauge Internal (0.005 mm) Internal (0.01 mm)	2.5 to 15 mm (10 to 180) mm	3 µm 6 µm	Gauge Blocks
¹ Thickness Gauge	Up to 20 mm (20 to 25) mm	0.6 µm 0.7 µm	Gauge Blocks
¹ Height Gauge (Dial and Digital)	Up to 20 mm (20 to 50) mm (50 to 100) mm (100 to 150) mm (150 to 200) mm (200 to 250) mm (250 to 300) mm (300 to 400) mm (400 to 500) mm (500 to 600) mm (600 to 700) mm (700 to 800) mm (800 to 900) mm (900 to 1 000) mm	0.6 µm 0.9 µm 1.5 µm 2.1 µm 2.8 µm 3.4 µm 4.1 µm 5.4 µm 6.8 µm 8.1 µm 9.5 µm 11 µm 12 µm 14 µm	Gauge Block Set
Feeler Gauge / Thickness Plate	Up to 1 mm (1 to 5) mm	0.21 µm 0.22 µm	ULM
Measuring Foil Standard Foil	Up to 1 mm (1 to 5) mm	0.21 µm 0.22 µm	ULM
¹ Indicator	Up to 20 mm (20 to 30) mm (30 to 40) mm (40 to 50) mm (50 to 60) mm (60 to 70) mm (70 to 80) mm (80 to 90) mm (90 to 100) mm	0.6 µm 0.7 µm 0.8 µm 0.9 µm 1 µm 1.1 µm 1.2 µm 1.3 µm 1.5 µm	Gauge Blocks
¹ Linear Length Gauge / Electrical Comparators / Mu Checker	Up to 5 mm (5 to 12) mm (12 to 20) mm (20 to 25) mm (25 to 50) mm	0.1 µm 0.2 µm 0.3 µm 0.4 µm 0.7 µm	Gauge Blocks

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Steel Ruler	Up to 100 mm	3 μ m	3D Vision Measuring Machine
	(100 to 200) mm	4 μ m	
	(200 to 300) mm	5 μ m	
	(300 to 400) mm	6 μ m	
	(400 to 500) mm	7 μ m	
	(500 to 600) mm	9 μ m	
	(600 to 700) mm	10 μ m	
	(700 to 800) mm	11 μ m	
	(800 to 900) mm	12 μ m	
	(900 to 1 200) mm	16 μ m	
	(1 200 to 1 500) mm	20 μ m	
(1 500 to 1 800) mm	24 μ m		
(1 800 to 2 000) mm	27 μ m		
Steel Tape & Textile Tape	Up to 200 mm	8 μ m	3D Vision Measuring Machine
	(200 to 400) mm	9 μ m	
	(400 to 600) mm	11 μ m	
	(600 to 800) mm	13 μ m	
	(800 to 1 000) mm	16 μ m	
	(1 000 to 1 200) mm	18 μ m	
(1 200 to 1 400) mm	20 μ m		
Steel Tape & Textile Tape	(1 400 to 1 600) mm	23 μ m	3D Vision Measuring Machine
	(1 600 to 1 800) mm	25 μ m	
	(1 800 to 2 000) mm	28 μ m	
	(2 000 to 3 000) mm	41 μ m	
	(3 000 to 4 000) mm	54 μ m	
	(4 000 to 5 000) mm	67 μ m	
	(5 000 to 6 000) mm	80 μ m	
	(6 000 to 7 000) mm	94 μ m	
	(7 000 to 8 000) mm	0.11 mm	
	(8 000 to 9 000) mm	0.12 mm	
	(9 000 to 10 000) mm	0.14 mm	
	(10 000 to 15 000) mm	0.2 mm	
	(15 000 to 20 000) mm	0.3 mm	
	(20 000 to 25 000) mm	0.34 mm	
	(25 000 to 30 000) mm	0.4 mm	
	(30 000 to 35 000) mm	0.47 mm	
(35 000 to 40 000) mm	0.54 mm		
(40 000 to 45 000) mm	0.6 mm		
(45 000 to 50 000) mm	0.67 mm		

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Depth Micro Checker, Step Gauge, Inside Checker, Anvil Block	Up to 100 mm (100 to 200) mm (200 to 250) mm (250 to 300) mm	2 μm 3 μm 4 μm 5 μm	Gauge Blocks, Linear Height Master
	Up to 25 mm	2 μm	
¹ Depth Gauge, Depth Micrometer	Up to 25 mm	0.7 μm	Gauge Block Set
	(25 to 50) mm	0.9 μm	
	(50 to 100) mm	1 μm	
	(100 to 150) mm	2 μm	
	(150 to 250) mm	3 μm	
	(250 to 300) mm	4 μm	
	(300 to 400) mm (400 to 450) mm	5 μm 6 μm	
¹ Surface Plate Overall Flatness Local Area Flatness (Repeat Reading)	Up to 4 m Diagonal (>4 to 10) m	1.5 μm 6.5 μm	Planekator (Straight Edge)
	Up to 0.1 μm	1 μm	Dial Indicator
Plain Plug Gauge, Pin Gauge, Three Wires, T-probe	Up to 15 mm	0.3 μm	ULM, Master Gauge Blocks
	(15 to 22) mm	0.4 μm	
	(22 to 30) mm	0.5 μm	
	(30 to 40) mm	0.6 μm	
	(40 to 50) mm	0.7 μm	
	(50 to 60) mm	0.9 μm	
	(60 to 70) mm	1 μm	
	(70 to 80) mm	1.2 μm	
	(80 to 90) mm	1.3 μm	
	(90 to 100) mm	1.4 μm	
	(100 to 150) mm	2 μm	
	(150 to 200) mm	2.7 μm	
	(200 to 250) mm (250 to 300) mm	3.4 μm 4 μm	

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Plain Ring Gauge	Up to 3 mm	0.44 μm	ULM, Master Plain Ring Gauges
	(3 to 6) mm	0.45 μm	
	(6 to 10) mm	0.46 μm	
	(10 to 12) mm	0.48 μm	
	(12 to 16) mm	0.5 μm	
	(16 to 18) mm	0.51 μm	
	(18 to 20) mm	0.53 μm	
	(20 to 22) mm	0.57 μm	
	(22 to 25) mm	0.59 μm	
	(25 to 28) mm	0.61 μm	
	(28 to 30) mm	0.63 μm	
	(30 to 75) mm	2.3 μm	
	(75 to 100) mm	3.1 μm	
(100 to 300) mm	4.9 μm		
¹ Check Master /Caliper Checker	Up to 100 mm	2.7 μm	Linear Height Master, Gauge Blocks
	(100 to 125) mm	2.9 μm	
	(125 to 150) mm	3.1 μm	
	(150 to 175) mm	3.3 μm	
	(175 to 200) mm	3.6 μm	
	(200 to 250) mm	4.1 μm	
	(250 to 300) mm	4.7 μm	
	(300 to 400) mm	5.9 μm	
	(400 to 500) mm	7.1 μm	
	(500 to 600) mm	8.4 μm	
(600 to 700) mm	9.7 μm		

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Thread Plug Gauges Pitch Diameter	(M2 to M10) mm (M10 to M20) mm (M20 to M50) mm (M50 to M70) mm (M70 to M100) mm (M100 to M150) mm	0.47 μm 0.49 μm 0.51 μm 0.55 μm 0.61 μm 0.63 μm	ULM, Thread Measuring Wire, Gauge Blocks
Major Diameter	(M2 to M10) mm (M10 to M20) mm (M20 to M30) mm (M30 to M40) mm (M40 to M50) mm (M50 to M60) mm (M60 to M70) mm (M70 to M80) mm (M80 to M90) mm (M90 to M100) mm (M100 to M125) mm (M125 to M150) mm	0.3 μm 0.4 μm 0.5 μm 0.6 μm 0.7 μm 0.9 μm 1 μm 1.2 μm 1.3 μm 1.4 μm 1.7 μm 2 μm	
Thread Ring Gauge Pitch Diameter	(M2 to M5) mm (M5 to M8) mm (M8 to M10) mm (M10 to M12) mm (M12 to M18) mm (M18 to M20) mm (M20 to M25) mm (M25 to M30) mm (M30 to M75) mm (M75 to M90) mm (M90 to M100) mm (M100 to M125) mm (M125 to M150) mm	0.57 μm 0.58 μm 0.59 μm 0.6 μm 0.63 μm 0.64 μm 0.68 μm 0.72 μm 2.3 μm 2.4 μm 2.5 μm 2.7 μm 2.9 μm	ULM, Plain Ring Gauges

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Thread Ring Gauge Minor Diameter	(M2 to M8) mm (M8 to M20) mm (M20 to M30) mm (M30 to M75) mm (M75 to M90) mm (M90 to M100) mm (M100 to M125) mm (M125 to M150) mm	0.4 µm 0.5 µm 0.6 µm 1.1 µm 1.3 µm 1.4 µm 1.8 µm 2.1 µm	ULM, Master Plain Ring Gauges
¹ Dial Gauge Tester, Calibration Tester	Up to 5 mm (5 to 12) mm (12 to 20) mm (20 to 25) mm (25 to 50) mm	0.65 µm 0.66 µm 0.68 µm 0.7 µm 0.73 µm	Liner Gauge w/Display
Plain Snap Gauge/Gap Gauge (External)	(2 to 4) mm (4 to 16) mm (16 to 22) mm (22 to 30) mm (30 to 75) mm (75 to 100) mm (100 to 200) mm (200 to 300) mm (300 to 400) mm (400 to 500) mm	0.2 µm 0.3 µm 0.4 µm 0.5 µm 1.1 µm 1.4 µm 2.7 µm 4 µm 5.4 µm 6.7 µm	ULM, Gauge Blocks
Plain Snap Gauge / Gap Gauge (Internal)	(2 to 6) mm (6 to 20) mm (20 to 30) mm (30 to 75) mm (75 to 100) mm (100 to 300) mm	0.4 µm 0.5 µm 0.6 µm 2.3 µm 2.4 µm 4.5 µm	ULM, Master Plain Ring Gauges
¹ Hole test, Three-Point Micrometer	(2 to 3) mm (3 to 8) mm (8 to 18) mm (18 to 20) mm (20 to 25) mm (25 to 28) mm (28 to 30) mm 75 mm	0.8 µm 0.9 µm 1.2 µm 1.3 µm 1.4 µm 1.5 µm 1.7 µm 3 µm	Master Ring Gauges
Dial Test Indicator	Up to 1.6 mm	0.3 µm	ULM

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Universal Length Measuring Machine	Up to 1 mm	0.06 μm	Gauge Blocks
	(1 to 3) mm	0.07 μm	
	(3 to 5) mm	0.09 μm	
	(5 to 10) mm	0.15 μm	
	(10 to 25) mm	0.34 μm	
	(25 to 50) mm	0.67 μm	
	(50 to 75) mm	1 μm	
	(75 to 100) mm	1.3 μm	
	(100 to 125) mm	1.7 μm	
	(125 to 150) mm	2.1 μm	
	(150 to 175) mm	2.4 μm	
	(175 to 200) mm	2.7 μm	
	(200 to 250) mm	3.4 μm	
	(250 to 300) mm	4.1 μm	
(300 to 400) mm	5.4 μm		
(400 to 500) mm	6.7 μm		
¹ Vernier Depth Gauge	Up to 200 mm	6 μm	Gauge Block Set
	(200 to 300) mm	7 μm	
	(300 to 400) mm	8 μm	
	(400 to 500) mm	9 μm	
	(500 to 600) mm	10 μm	
	(600 to 700) mm	11 μm	
	(700 to 800) mm	12 μm	
	(800 to 900) mm	13 μm	
	(900 to 1 000) mm	15 μm	
Bore Gauge / Cylinder Gauge	(0.5 to 10) mm	0.6 μm	ULM, Gauge Blocks
	(10 to 30) mm	0.8 μm	
	(30 to 50) mm	0.9 μm	
	(50 to 70) mm	1.1 μm	
	(70 to 100) mm	1.5 μm	
	(100 to 125) mm	1.8 μm	
	(125 to 150) mm	2.1 μm	
	(150 to 175) mm	2.5 μm	
	(175 to 200) mm	2.8 μm	
	(200 to 250) mm	3.5 μm	
	(250 to 300) mm	4.1 μm	
	(300 to 400) mm	5.4 μm	
	(400 to 500) mm	6.8 μm	
(500 to 600) mm	8.1 μm		
(600 to 700) mm	9.5 μm		
(700 to 800) mm	11 μm		

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
^{1,3} Profile Projector Linearity	Up to 50 mm (50 to 200) mm (200 to 410) mm	2 μm 3 μm 7 μm	Glass Scale
Angle	(0.25 to 30) °	12"	Angle Block Set
¹ Measuring Microscope, Optical Comparator, 3D Vision Measuring System	Up to 50 mm (50 to 200) mm (200 to 410) mm	2 μm 3 μm 7 μm	Glass Scale
¹ Height Master	Up to 175 mm (175 to 250) mm (250 to 300) mm (300 to 400) mm (400 to 500) mm (500 to 600) mm (600 to 700) mm	3 μm 4 μm 5 μm 6 μm 7 μm 8 μm 10 μm	Gauge Block / Linear Height Master
³ Bevel Protractor	Up to 30 ° (30 to 45) ° (45 to 90) °	12" 24" 48"	Angle Block
	Up to 100 mm (100 to 200) mm (200 to 300) mm	3 μm 4 μm 5 μm	3D Vision Measuring Machine
Chamfer Gauge	Up to 10 mm	3 μm	3D Vision Measuring Machine
Pitch Gauge	Up to 7 mm	3 μm	3D Vision Measuring Machine
Radius Gauge	Up to 100 mm	3 μm	3D Vision Measuring Machine
Taper Gauge (Scale Type)	Up to 100 mm	3 μm	3D Vision Measuring Machine
Taper Thread Ring	M2 to M5 M5 to M11 M11 to M22 M22 to M45 M45 to M180	0.9 μm 0.91 μm 1.8 μm 5.1 μm 11 μm	ULM, Ring Gauge
¹ Riser Block	150 mm 300 mm 600 mm	9 μm 10 μm 12 μm	Linear Height Master, Gauge Blocks

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Long Gauge Block (Grade 1, 2)	100 mm (100 to 125) mm (125 to 150) mm (150 to 175) mm (175 to 200) mm (200 to 250) mm (250 to 300) mm (300 to 400) mm (400 to 500) mm	1.3 μm 1.7 μm 2.1 μm 2.4 μm 2.7 μm 3.4 μm 4.1 μm 5.4 μm 6.7 μm	ULM, Master Gauge Blocks
Standard Micrometer, Setting Rod, Length Bar	Up to 25 mm (25 to 50) mm (50 to 75) mm (75 to 100) mm (100 to 125) mm (125 to 150) mm (150 to 175) mm (175 to 200) mm (200 to 300) mm (300 to 400) mm (400 to 500) mm	0.4 μm 0.7 μm 1.1 μm 1.4 μm 1.7 μm 2 μm 2.4 μm 2.7 μm 4 μm 5.4 μm 6.7 μm	ULM, Gauge Blocks
Angle Block / Angular	(0.25 to 30) ° (30 to 45) ° (45 to 60) ° (60 to 90) °	12" 24" 36" 48"	Angle Block, 3D Vision Measuring Machine
Gauge Blocks	1 mm (1 to 5) mm (5 to 10) mm (10 to 25) mm (25 to 50) mm (50 to 75) mm (75 to 100) mm	0.22 μm 0.23 μm 0.26 μm 0.43 μm 0.72 μm 1.1 μm 1.4 μm	ULM, Master Gauge Blocks
Test Sieve	Up to 50 mm	3 μm	3D Vision Measuring Machine

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Taper Plug Gauges	Up to M7 M7 to M15 M15 to M25 M25 to M30 M30 to M40 M40 to M50 M50 to M60 M60 to M70 M70 to M80 M80 to M90 M90 to M100 M100 to M200 M200 to M300	0.2 μm 0.3 μm 0.4 μm 0.5 μm 0.6 μm 0.7 μm 0.9 μm 1 μm 1.1 μm 1.3 μm 1.4 μm 2.7 μm 4 μm	ULM, Gauge Blocks
Taper Ring Gauge	M2 to M6 M6 to M20 M20 to M30 M30 to M75 M75 to M100 M100 to M150	0.4 μm 0.5 μm 0.6 μm 2.3 μm 2.4 μm 2.9 μm	ULM, Ring Gauges
Taper Thread Plug	M2 to M5 M5 to M11 M11 to M22 M22 to M45 M45 to M180	0.92 μm 1.8 μm 1.1 μm 4.7 μm 7.6 μm	ULM, Thread Measuring Wire
¹ Coordinate Measuring Machine X, Y, Z Axis	Up to 10 mm (10 to 25) mm (25 to 50) mm (50 to 75) mm (75 to 100) mm (100 to 125) mm (125 to 150) mm (150 to 175) mm (175 to 200) mm (200 to 250) mm (250 to 300) mm (300 to 400) mm (400 to 500) mm (500 to 800) mm (800 to 1 000) mm (1 000 to 1 200) mm (1 200 to 1 500) mm	0.16 μm 0.34 μm 0.67 μm 1 μm 1.3 μm 1.7 μm 2.1 μm 2.4 μm 2.7 μm 3.4 μm 4.1 μm 5.4 μm 6.7 μm 11 μm 13 μm 16 μm 20 μm	Gauge Blocks

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Ultrasonic Thickness Gauge	Up to 100 mm	6 nm	Gauge Blocks
Standard Scale	Up to 50 mm. (> 50 to 200) mm (> 200 to 410) mm	1.3 μm 2.4 μm 3.4 μm	3D Vision Measuring Machine, Standard Glass Scale
Coating Thickness Gauge	(30 to 1 470) μm	0.92 μm	Calibration Foils
Square	Up to 100 mm (> 100 to 200) mm (> 200 to 300) mm (> 300 to 400) mm (> 400 to 500) mm (>500 to 700) mm	3.1 μm 3.8 μm 4.5 μm 6 μm 7.2 μm 9.8 μm	Coordinate Measuring Machine

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Electronic Balance, Spring Balance, Load Cell Resolution: 0.000 01 g	Up to 10 g	0.04 mg	OIML Class E2, F1, M1 weight sets and internal calibration procedure utilized in the calibration of the weighing system.
0.000 01 g	(10 to 20) g	0.05 mg	
0.000 01 g	(20 to 50) g	0.08 mg	
0.000 01 g	(50 to 60) g	0.11 mg	
0.000 01 g	(60 to 70) g	0.12 mg	
0.000 01 g	(70 to 100) g	0.16 mg	
0.000 1 g	(100 to 150) g	0.2 mg	
0.000 1 g	(150 to 220) g	0.3 mg	
0.000 1 g	(220 to 300) g	0.4 mg	



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Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Electronic Balance, Spring Balance, Load Cell Resolution: 0.001 g 0.001 g 0.001 g 0.001 g 0.001 g 0.001 g 0.01 g 0.01 g 0.01 g 0.01 kg 0.1 kg 0.5 kg 1 kg 5 kg 10 kg	(300 to 1 000) g (1 000 to 2 000) g (2 to 3) kg (3 to 5) kg (5 to 6) kg (6 to 8) kg (8 to 10) kg (10 to 12) kg (12 to 20) kg (20 to 100) kg (100 to 1 000) kg (1 000 to 5 000) kg (5 000 to 10 000) kg (10 000 to 40 000) kg (40 000 to 80 000) kg	1 mg 2 mg 3 mg 5 mg 10 mg 12 mg 17 mg 20 mg 26 mg 5.8 g 58 g 0.33 kg 0.66 kg 3.2 kg 6.3 kg	OIML Class E2, F1, M1 weight sets and internal calibration procedure utilized in the calibration of the weighing system.
¹ Push-Pull Gauge, Force Gauge, Tension, Tensile	Up to 1 000 N (1 000 to 3 000) N (3 000 to 5 000) N (5 000 to 10 000) N	0.006 N 0.01 N 0.02 N 0.03 N	Weight Sets
¹ Hand Torque Tool, Torque Wrench, Torque Driver, Electronic Torque	(0.2 to 20) N·m (20 to 40) N·m (40 to 60) N·m (60 to 80) N·m (80 to 100) N·m (100 to 200) N·m (200 to 400) N·m (400 to 600) N·m (600 to 800) N·m (800 to 1 000) N·m	0.06 N·m 0.07 N·m 0.08 N·m 0.09 N·m 0.1 N·m 3.1 N·m 3.5 N·m 3.9 N·m 4.4 N·m 5 N·m	Static Torque Transducer
¹ Hardness Tester, Duro Tester Type (A, B, O) (Spring Force Only)	(Up to 30) Duro (30 to 40) Duro (40 to 100) Duro	0.6 Duro 0.7 Duro 0.9 Duro	Weight Set

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Hardness Tester, Duro Tester Type (C, D, DO) (Spring Force Only)	Up to 20 Duro (20 to 30) Duro (30 to 40) Duro (40 to 50) Duro (50 to 60) Duro (60 to 70) Duro (70 to 80) Duro (80 to 90) Duro (90 to 100) Duro	1.2 Duro 2.1 Duro 2.4 Duro 2.3 Duro 2.7 Duro 3.9 Duro 4.3 Duro 6.1 Duro 6.5 Duro	Weight Set
Manometer	Up to 1 psig	0.001 9 psi	Fluke 700PD2 Pressure Module
¹ Pneumatic Pressure Devices	Up to 200 kPa (> 200 to 2 000) kPa	0.06 kPa 0.58 kPa	Pneumatic Pressure Calibrator
¹ Hydraulic Pressure Devices	Up to 7 MPa (> 7 to 70) MPa	4 kPa 21 kPa	Hydraulic Pressure Calibrator
¹ Vacuum Gauges	(-90 to 0) kPa	55 Pa	Vacuum Calibrator
Mass (Standard Weights)	10 mg 20 mg 50 mg 100 mg 200 mg 500 mg 1 g 2 g 5 g 10 g 20 g 50 g 100 g 200 g 500 g 1 kg 2 kg 5 kg 10 kg 20 kg	13 µg 14 µg 24 µg 26 µg 27 µg 30 µg 12 µg 14 µg 18 µg 24 µg 35 µg 87 µg 0.14 mg 0.26 mg 0.85 mg 2.1 mg 6.9 mg 11 mg 61 mg 69 mg	Electronic Balance, OIML Class E2, F1, and M1 Weights
Mass (Standard Weights)	50 kg 100 kg 200 kg 500 kg	1 g 1 g 5 g 5 g	Electronic Balance, OIML Class F2 Weights

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Torque Calibrators	(0.1 to 2) N·m (2 to 4) N·m (4 to 6) N·m (6 to 8) N·m (8 to 10) N·m (10 to 20) N·m (20 to 40) N·m (40 to 200) N·m (200 to 400) N·m (400 to 1 000) N·m (1 000 to 1 500) N·m	0.92 % of reading 0.46 % of reading 0.31 % of reading 0.23 % of reading 0.18 % of reading 0.1 % of reading 0.05 % of reading 0.03 % of reading 0.02 % of reading 0.01 % of reading 0.006 % of reading	Weights, Calibration Arms
¹ Universal Testing Machine, Crane Scales, Compression / Tensile Testing Machine	Compression Testing Machine (0.10 to 200) kN Tensile Testing Machine 100 N to 30 kN	0.32 % of reading 0.16 % of reading	Master Load Cell
Volumetric Glassware, Burette	5 ml 10 ml 25 ml 50 ml 100 ml	0.003 5 ml 0.003 7 ml 0.006 5 ml 0.01 ml 0.018 ml	Electronic Balance
Volumetric Glassware, Volumetric Flask	2 ml 5 ml 10 ml 20 ml 25 ml 50 ml 100 ml 200 ml 250 ml 500 ml 1 000 ml	0.005 8 ml 0.005 8 ml 0.005 9 ml 0.006 2 ml 0.006 5 ml 0.01 ml 0.017 ml 0.028 ml 0.035 ml 0.063 ml 0.13 ml	Electronic Balance
Volumetric Glassware, Measuring Cylinder	5 ml 10 ml 25 ml 50 ml 100 ml 250 ml 500 ml 1 000 ml	0.005 8 ml 0.005 9 ml 0.006 5 ml 0.01 ml 0.017 ml 0.035 ml 0.063 ml 0.13 ml	Electronic Balance

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Volumetric Glassware, Measuring Pipette	0.5 ml 1 ml 2 ml 5 ml 10 ml 15 ml 25 ml 50 ml	0.002 3 ml 0.002 3 ml 0.002 3 ml 0.002 4 ml 0.003 7 ml 0.006 ml 0.006 5 ml 0.01 ml	Electronic Balance
Volumetric Glassware, Volumetric Pipette	0.5 ml 1 ml 2 ml 5 ml 10 ml 15 ml 25 ml 50 ml 100 ml	0.002 3 ml 0.002 3 ml 0.00 23 ml 0.002 4 ml 0.003 7 ml 0.006 ml 0.006 5 ml 0.01 ml 0.016 ml	Electronic Balance
Piston Pipette	(10 to 1 000) µl	0.14 µl	Electronic Balance
¹ Anemometers (Air Velocity)	2.5 m/s 5 m/s 7.5 m/s 10 m/s 12.5 m/s 15 m/s	0.25 m/s 0.25 m/s 0.25 m/s 0.25 m/s 0.42 m/s 0.42 m/s	Lutron MHB-382SD Barometer, Trotec TA400 Dynamic Pressure Anemometer, Omega WTM-1000 Wind Tunnel
Liquid Flow Devices	(1 to 3) m ³ /h (3 to 6) m ³ /h (6 to 10) m ³ /h (10 to 20) m ³ /h (20 to 30) m ³ /h	0.051 m ³ /h 0.018 m ³ /h 0.065 m ³ /h 0.069 m ³ /h 0.099 m ³ /h	Ultrasonic Flow Meter, Calibration Rig
Liquid Flow Devices	(1 to 6) m ³ /h (6 to 12) m ³ /h (12 to 24) m ³ /h (24 to 42) m ³ /h	0.029 m ³ /h 0.037 m ³ /h 0.056 m ³ /h 0.069 m ³ /h	Electromagnetic Flow Meter, Calibration Rig
Air Flow Meters	Up to 50 l/min (50 to 100) l/min (100 to 150) l/min (150 to 200) l/min	3.4 l/min 3.8 l/min 4.1 l/min 7.5 l/min	Air Flow Calibrator, Calibration Rig

Photometry and Radiometry

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
^{1,3} Gloss Meters	(0 to 100) GU		Standard Gloss Tile
	20 °	0.93 GU	
	60 °	0.91 GU	
	85 °	1.1 GU	

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Temperature Controlled Chamber, Hot Air Oven, Incubator, Refrigerator, Low Temperature Incubator, Autoclave	(-40.0 to 0) °C	0.27 °C	Agilent 34970A Data logger and Thermocouple with RTD sensor
	(0 to 100) °C	0.19 °C	
	(100 to 200) °C	0.26 °C	
	(200 to 250) °C	0.31 °C	
¹ Temperature Gauge & Dial Thermometer	(-80 to 250) °C	0.07 °C	Hart Scientific 1575 PRT Standard
	(250 to 500) °C	0.7 °C	Fluke 1524 Thermocouple Standard
	(500 to 650) °C	2.6 °C	
¹ Thermocouple Sensor TC	(-80 to 250) °C	0.07 °C	Hart Scientific 1575 PRT Standard
	(250 to 500) °C	0.7 °C	Fluke 1524 Thermocouple Standard
	(500 to 1 200) °C	2.6 °C	
¹ Liquid Bath	(-40.0 to 0) °C	0.27 °C	Agilent 34970A Data logger and Thermocouple with RTD sensor
	(0 to 100) °C	0.19 °C	
	(100 to 200) °C	0.26 °C	
	(200 to 250) °C	0.31 °C	
¹ Digital Thermometer with Thermocouple Sensors Types K, J, E, T, N, R, S	(-80 to 250) °C	0.07 °C	Hart Scientific 1575 PRT Standard
	(250 to 500) °C	0.7 °C	Fluke 1524 Thermocouple Standard
	(500 to 1 200) °C	2.6 °C	
¹ Digital Thermometer with RTD or Thermistor Sensor	(-80 to 250) °C	0.07 °C	Hart Scientific 1575 PRT Standard
	(250 to 500) °C	0.7 °C	Fluke 1524 Thermocouple Standard
	(500 to 850) °C	2.6 °C	
¹ RTD Sensor	(-80 to 250) °C	0.07 °C	Hart Scientific 1575 PRT Standard
	(250 to 500) °C	0.7 °C	Fluke 1524 Thermocouple Standard
	(500 to 850) °C	2.6 °C	
Liquid-in-Glass Thermometers	(-80 to 250) °C	0.29 °C	Hart Scientific 1575 PRT Standard

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Dry Block, Dry Well	Up to 250 °C	0.07 °C	Hart Scientific 1575 PRT Standard
	(250 to 450) °C (450 to 1 200) °C	0.7 °C 2.6 °C	Thermocouple Standard
¹ Furnace	(300 to 600) °C	1.8 °C	Thermocouple Standard
	(600 to 900) °C	2.5 °C	
	(900 to 1 200) °C	2.6 °C	
Digital Thermometer with Surface Probe	(40 to 350) °C	2.4 °C	Digital Thermometer Fluke 714 with Surface Probe
Infrared Thermometers	(-40 to 50) °C	0.91 °C	Comparison to Radiation Thermometer $\epsilon = 0.95, \lambda = (8 \text{ to } 14) \mu\text{m}$
	(>50 to 100) °C	0.92 °C	
	(>100 to 200) °C	1.5 °C	
	(>200 to 400) °C	2 °C	
Thermo Hygrometer Temperature	(15 to 40) °C	0.5 °C	Fluke 5020A Thermo-hygrometer, Temp/Humidity Chamber
Thermo Hygrometer Humidity	(30 to 50) %RH	1.6 %RH	Fluke 5020A Thermo-hygrometer, Temp/Humidity Chamber
	(50 to 70) %RH	2 %RH	
	(70 to 90) %RH	2.3 %RH	
Thermo Hygrometer Temperature Chamber	(20 to 40) °C	0.11 °C	Agilent 34901A Datalogger with RTD sensor
Thermo Hygrometer Humidity Chamber	(30 to 70) %RH	3.3 %RH	Comparison to Data Logger CEM DT-172

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Digital Photo Tachometers	(2.5 to 999.9) rpm	0.01 rpm	Fluke 5502A Multiproduct Calibrator with LED
	(> 999.9 to 9 999.9) rpm	0.06 rpm	
	(> 9 999.9 to 99 999) rpm	0.58 rpm	
¹ Digital Contact Tachometers	(0.5 to 999.9) rpm	0.01 rpm	Fluke 5502A Multiproduct Calibrator
	(> 999.9 to 9 999.9) rpm	0.06 rpm	
	(> 9 999.9 to 19 999) rpm	0.58 rpm	

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
¹ Stroboscopes	Up to 120 rpm (> 120 to 1 020) rpm (> 1 020 to 5 040) rpm (> 5 040 to 10 020) rpm (>10 020 to 20 040) rpm (> 20 040 to 50 040) rpm (50 040 to 99 960) rpm	0.1 rpm 0.1 rpm 0.22 rpm 0.36 rpm 0.65 rpm 1.52 rpm 2.96 rpm	Fluke PM6685 Universal Counter, High-Speed Photo Transistor Box (PT523C-B1-T363)
¹ Stopwatch Photo Totalize Method Time Base Method	10 s to 1 hr (1 to 86 400) s	27 ms 0.58 ms	Agilent 53132A Universal Frequency Counter, Fluke PM6685R Universal Frequency Counter, HP 8904A Multifunction Synthesizer
¹ Frequency Source	(0.01 to 500) Hz 500 Hz to 5 kHz (5 to 50) kHz	20 μHz/Hz + 5.9 mHz 20 μHz/Hz + 58 mHz 20 μHz/Hz + 0.58 Hz	Fluke 5502A Multiproduct Calibrator
³ General Frequency Source	(1 to 1 000) Hz >1Hz to 10 kHz (>0.01 to 225) MHz (>225 to 300) MHz >300 MHz to 1 GHz (>1 to 1.8) GHz (>1.8 to 18) GHz	4.4 x 10 ⁻¹⁰ f 2.4 x 10 ⁻¹⁰ f 2.4 x 10 ⁻¹⁰ f 2.4 x 10 ⁻⁹ f 7 x 10 ⁻¹⁰ f 4.2 x 10 ⁻¹⁰ f 2.7 x 10 ⁻¹⁰ f	Agilent 53132A Universal Frequency Counter, Fluke PM6685R Universal Frequency Counter, HP 8902A Measuring Receiver
Radar Gun Speed	24.150 GHz 40.25 km/h 56.35 km/h 104.65 km/h 34.7 GHz 40.64 km/h 64.75 km/h	1 km/h 1 km/h	Using Tuning Forks
¹ Radar Speed (All Frequency Band)	60 km/h 90 km/h 120 km/h	0.4 km/h 0.6 km/h 0.9 km/h	Rasmi Racing Drag and Timer, Measuring Tape, Calculate speed (S) by known distance (D) and known elapse time (T) $S = \frac{D}{T}$
¹ Centrifuge	(50.00 to 999.99) rpm (1 000.0 to 3 000.0) rpm (3 000.1 to 9 999.9) rpm (10 000 to 20 000) rpm	0.53 rpm 1.9 rpm 5.3 rpm 13 rpm	Digital Tachometer

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Universal Frequency Counter	Time Base 1 MHz to 10 MHz	2.4 x 10 ⁻¹⁰ Hz	Agilent 53132A Universal Frequency Counter, Fluke PM6685R Universal Frequency Counter, Agilent N9310A RF Signal Generator, HP 33120A Function Generator/Arbitrary Waveform Generator, HP 83731A Synthesizer Signal Generator, HP 8904A Multifunction Synthesizer
	Frequency DC to 18 GHz	2.9 x 10 ⁻¹⁰ Hz	
	Time Interval 1 μs to 1 ms	0.6 ps	
	Trigger Level (-5.25 to 5.25) V	1.9 μV	
Time Interval Source	10 ns to 1 s	2 ns	Agilent 53132A Universal Frequency Counter, Fluke PM6685R Universal Frequency Counter
	(> 1 to 10) s	4 ns	
	(> 10 to 50) s	14 ns	
	(> 50 to 100) s	26 ns	

DIMENSIONAL MEASUREMENT

1 Dimensional

Parameter	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Jig, Fixture and Mold, Die X-axis	Up to 25 mm	0.002 7 mm	Coordinate Measuring Machine
	(25 to 50) mm	0.002 8 mm	
	(50 to 75) mm	0.002 9 mm	
	(75 to 100) mm	0.003 mm	
	(100 to 125) mm	0.003 2 mm	
	(125 to 150) mm	0.003 4 mm	
	(150 to 175) mm	0.003 6 mm	
	(175 to 200) mm	0.003 8 mm	
	(200 to 250) mm	0.004 3 mm	
	(250 to 300) mm	0.004 9 mm	
	(300 to 400) mm	0.006 mm	
	(400 to 500) mm	0.007 2 mm	
(500 to 600) mm	0.008 5 mm		


1 Dimensional

Parameter	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Jig, Fixture and Mold, Die Y-axis	Up to 25 mm	0.002 7 mm	Coordinate Measuring Machine
	(25 to 50) mm	0.002 8 mm	
	(50 to 75) mm	0.002 9 mm	
	(75 to 100) mm	0.003 mm	
	(100 to 125) mm	0.003 2 mm	
	(125 to 150) mm	0.003 4 mm	
	(150 to 175) mm	0.003 6 mm	
	(175 to 200) mm	0.003 8 mm	
	(200 to 250) mm	0.004 3 mm	
	(250 to 300) mm	0.004 9 mm	
	(300 to 400) mm	0.006 mm	
	(400 to 500) mm	0.007 2 mm	
(500 to 700) mm	0.009 8 mm		
Jig, Fixture and Mold, Die Z-axis	Up to 25 mm	0.002 7 mm	Coordinate Measuring Machine
	(25 to 50) mm	0.002 8 mm	
	(50 to 75) mm	0.002 9 mm	
	(75 to 100) mm	0.003 mm	
	(100 to 125) mm	0.003 2 mm	
	(125 to 150) mm	0.003 4 mm	
	(150 to 175) mm	0.003 6 mm	
	(175 to 200) mm	0.003 8 mm	
	(200 to 250) mm	0.004 3 mm	
	(250 to 300) mm	0.004 9 mm	
	(300 to 400) mm	0.006 mm	
	(400 to 500) mm	0.007 2 mm	

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. Nominal Values listed as approximate.
3. f = frequency in Hz; " = arc-second; GU = Gloss Units.
4. Mismatch Uncertainty is based on DUT SWR: 1.4 for <2 GHz; 1.6 for <18 GHz.
5. This scope is formatted as part of a single document including Certificate of Accreditation No. ACT-2050.



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